

# **Notice of References Cited**

Application/Control No.

09/653,149

Applicant(s)/Patent Under  
Reexamination  
DERDERIAN ET AL.

Examiner

Thao P Le

Art Unit

2818

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## **U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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	B	US-6218256-	04-2001	Agarwal	438	393
*	C	US-6104049-	08-2000	Solayappan et al.	257	295
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		Country Code-Number-Kind Code	MM-YYYY				
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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